

Notice of References Cited	Application/Control No. 10/784,242	Applicant(s)/Patent Under Reexamination OISHI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0073846	04-2005	Takine, Kenji	362/296
	B	US-2004/0065894	04-2004	Hashimoto et al.	257/100
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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